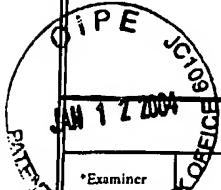


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SL	AA 6,024,847	02-2000	Rosenberg et al.			
SL	AB 2,949,357	08-1960	Resnick			
SL	AC 5,171,379	12-1992	Kumar et al.			
SL	AD 5,403,458	04-1995	Hartig et al.			
SL	AE 5,209,835	05-1993	Makino et al.			

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AP	JP1092550	04/1990	Japan				
AG	GB 810533	03/1959	GB				
AH	JP57019372	02/1982	Japan				
AI	JP200273623	10/2000	Japan				
AJ	SU1582683	09/1996	SU				
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AN	Hughes et al., "Grain Subdivision and the Development of Local Orientations in Rolled Tantalum" Tantalum, The Minerals, Metals & Materials Society, 1996, pgs. 257-262. (Year is sufficiently early so that the month is not an issue.)
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AP	Arlt, Jr., "Sulfonation and Sulfonation to Thorium and Thorium Compounds" Kirk-Othmer Encyclopedia of chemical Technology vol. 22, pp. 341-364, (1993, Year is sufficiently early so that the month is not an issue.)
AQ	Kumar, et al. "Effect of Intermetallic Compounds of the Properties of Tantalum" Materials Research Society Symposium Proceedings, vol. 322, pgs. 413-422, 1994. (Year is sufficiently early so that the month is not an issue.)
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AS	National Research Corporation Press Release, pgs. 1-4, July 1964.
AT	National Research Corporation Data Sheet "SGS Tantalum", pgs. 1-7, no date.
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AV	Klein et al., "Inhomogeneous Textures in Tantalum Sheets" Materials Science Forum, vol. 157-162, pgs. 1423, (1994). (Year is sufficiently early so that the month is not an issue.)
AW	Clark et al., "Influence of Transverse Rolling on the Microstructural and Texture Development in Pure Tantalum", Metallurgical Transactions, vol. 23A, pgs. 2183-2191, August 1992.

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AB	4,903,117	02-1990	Okamoto et al.			
AC	6,521,173	02-2003	Kumar et al.			
AD	5,372,659	12-1994	Lamaze et al.			
AE	4,830,665	05-1989	Winand			

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						Yes	No
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AG	0 442 752 A1	08/91	EP				
AH	0 928 977 A1	07/99	EP				
AI	JP61031992A	02/86	JP (abstract)				
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AN	Raabe, et al., "Texture and Microstructure of Rolled and Annealed Tantalum", Materials Science and Technology, Vol. 10, pgs. 299-305, April 1994.
AO	Wright et al., "Texture Gradient Effects in Tantalum", International Conference on Textures of Materials, 7 pgs., September 1993.
AP	Wright et al., "Textural and Microstructural Gradient Effects on the Mechanical Behavior of a Tantalum Plate", Metallurgical Transactions A, 25A (1994), pgs. 1-17. (Year is sufficiently early so that the month is not an issue.)
AQ	Clark et al., "Effect of Processing Variables on Texture and Texture Gradients in Tantalum", Metallurgical Transactions A, Vol. 22A, September 1991, pgs. 2039-2047.
AR	Kumar et al., "Corrosion Resistant Properties of Tantalum" Corrosion 95, Paper No. 253, 14 pages. (No date)
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Sh	AB 6,451,402 B1	09-2002	Nee			
Sh	AC 6,417,105 B1	07-2002	Shah et al.			
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						Yes	No
Sh	AF EP0872572 A1	10-1998	EPO				
Sh	AG WO 98/49357	11-1998	PCT				
Sh	AH WO 00/13235	09/03/2000	PCT				
Sh	AI U8120445	14/05/1996	Japan				
Sh	AJ FR 2 585 730 A1	08/01/1985	France				
Sh	AK GB 2 202 237 A	21/09/1988	GB				
Sh	AL 11074348	16/03/1999	Japan				
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Sh	AN	Knotek et al., "The Structure and Composition of Ti-Zr-N, Ti-Al-Zr-N and Ti-Al-V-N Coatings" Materials Science and Engineering, A105/106, December 1988, pgs. 481-488.
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Sh	AP	Sakamoto et al., "Preparation and Microstructure of Reactively Sputtered Ti _x Zr _y N Films" Thin Solid Films 228, May 1993, pgs. 169-172.
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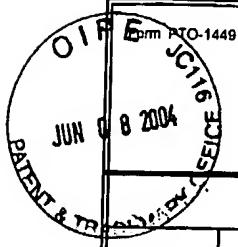
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John P. Shuler

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11-29-04

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<i>Sh</i>	AA	4,895,770	01-1990	Schintlmeister et al.			
<i>Sh</i>	AB	6,396,207	05-2002	Hasegawa et al.			
<i>Sh</i>	AC	6,210,634	04-2001	Ishigami et al.			
	AD						
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	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
<i>Sh</i>	AM	JP08255912	01-1996	Japan			Yes <input checked="" type="checkbox"/> No <input type="checkbox"/>
	AN						X
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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	AT						
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					FILING DATE September 22, 2003	GROUP 1742	
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<i>JL</i>	AA	6,339,593	05-2003	Hecks et al.			
<i>JL</i>	AB	6,462,302 B1	12-2002	LJ et al.			
<i>JL</i>	AC	6,723,187 B2	04-2004	Segal et al.			
<i>JL</i>	AD	2003/0132108 A1	07-2003	Takahashi et al.			Jan. 14, 2003
	AB						
	AP						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AM						Yes
	AN						No
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER	<i>John E. Ollie</i>			DATE CONSIDERED	<i>11-29-2004</i>		
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<i>John P. Shul</i>	AA	6,176,944 B1	01-2001	Snowman et al.				
<i>John P. Shul</i>	AB	6,063,254	05-2000	Rosenberg et al.				
<i>John P. Shul</i>	AC	4,189,358	02-1980	Scarpellino, Jr. et al.				
<i>John P. Shul</i>	AD	US2004/0025986A1	02-2004	Perry et al.			Aug. 8, 2002	
<i>John P. Shul</i>	AE	US2004/0011432A1	01-2004	Podlaha et al.			Jul. 17, 2002	
	AF							
	AG							
	AH							
	AJ							
	AJ							
	AK							
	AL							
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		Document Number	Date	Country	Class	Subclass	Translation	
<i>John P. Shul</i>	AM	363014864A	01-1988	Japan (abstract only)			Yes	No
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
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	AT							
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